The NCSLI Tennessee Section held its spring meeting on May 1, 2018 at the Oak Ridge National Laboratory (ORNL) in Oak Ridge, Tennessee with 52 people in attendance. There were several outstanding presentations we began with “The New ISO/IEC 17025” Standard” by Internal Accreditation Service’s (IAS) Helga Alexander. The next was a presentation titled “Designing Flowmeter Calibration Test Plans” by CEESI’s Tom Kegel. After that the audience watched a presentation called “Calibration Issues related to Surface Finish and Standardization” by Mitutoyo’s Jeremy Adcox. Fluke’s Scott Peterson spoke on “Advantages of Calibration Automation & Asset Management Software.” The last talk was titled “Primary-Level Metrology Capabilities at the Oak Ridge National Laboratory (ORNL)” by ORNL’s Greg Strickland, Joe Keck and Mike Duncan. To close out the meeting, the Oak Ridge National Laboratory’s metrology staff hosted tours of the ORNL Metrology laboratory, the historic ORNL Graphite Reactor and the ORNL Exoscale Computing Center. Lunch for all attendees was sponsored by Mitutoyo America.

The Tennessee Section meeting was part of a pilot, cooperative effort between the Huntsville, Alabama and Birmingham, Alabama sections to schedule meetings back-to-back. The purpose of this effort was to provide presenters an opportunity to travel to one meeting and have opportunities to present over a consecutive three-day period at three separate section meetings. The cooperative effort was met enthusiastically by presenters and their companies and will likely be typical of future section meetings.